

Search Notes

Application/Control No.

10/730,850

Examiner

Randall Chin

Applicant(s)/Patent under
Reexamination

CHAN, JOHN GEOFFREY

Art Unit

1744

SEARCHED

Class	Subclass	Date	Examiner
15	22.1	↓	↓
15	22.2	↓	↓
15	28	5/17/2007	RC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST, OCR, EPO, JPO, DERWENT	↓	↓
Inventor name search	5/17/2007	RC